

April 1992 Revised March 2002

## 74ABT162244

# 16-Bit Buffer/Line Driver with 25 $\Omega$ Series Resistors in the Outputs

#### **General Description**

The ABT162244 contains sixteen non-inverting buffers with 3-STATE outputs designed to be employed as a memory and address driver, clock driver, or bus oriented transmitter/receiver. The device is nibble controlled. Individual 3-STATE control inputs can be shorted together for 8-bit or 16-bit operation.

The  $25\Omega$  series resistors in the outputs reduce ringing and eliminate the need for external resistors.

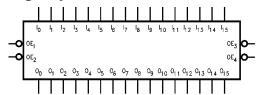
#### **Features**

- Separate control logic for each nibble
- 16-bit version of the ABT2244
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Non-destructive hot insertion capability

## **Ordering Code:**

Order Number	Package Number	Package Description
74ABT162244CSSC	MS48A	48-Lead Small Shrink Outline Package (SSOP), JEDEC MO-118, 0.300" Wide
74ABT162244CSSX	MS48A	48-Lead Small Shrink Outline Package (SSOP), JEDEC MO-118, 0.300" Wide
74ABT162244CMTD	MTD48	48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide
74ABT162244MTDX	MTD48	48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide

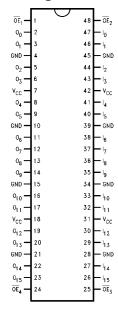
## **Logic Symbol**



#### **Pin Descriptions**

Pin Names	Description	
<del>OE</del> n	Output Enable Input (Active LOW)	
I <sub>0</sub> -I <sub>15</sub>	Inputs	
O <sub>0</sub> -O <sub>15</sub>	Outputs	

## **Connection Diagram**



## **Truth Tables**

Inp	outs	Outputs
OE <sub>1</sub>	I <sub>0</sub> -I <sub>3</sub>	O <sub>0</sub> -O <sub>3</sub>
L	L	L
L	Н	Н
Н	Х	Z

Inj	Inputs		
ŌE <sub>3</sub>	I <sub>8</sub> -I <sub>11</sub>	O <sub>8</sub> -O <sub>11</sub>	
L	L	L	
L	Н	Н	
Н	X	Z	

In	Outputs	
OE <sub>2</sub>	I <sub>4</sub> –I <sub>7</sub>	04-04
L	L	L
L	Н	Н
Н	X	Z

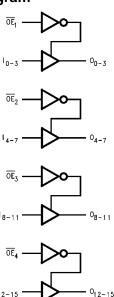
In	puts	Outputs
OE <sub>4</sub>	I <sub>12</sub> -I <sub>15</sub>	O <sub>12</sub> -O <sub>15</sub>
L	L	L
L	Н	Н
н	X	Z

- H = HIGH Voltage Level
  L = LOW Voltage Level
  X = Immaterial
  Z = High Impedance

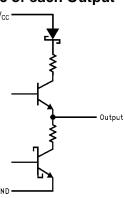
## **Functional Description**

The ABT162244 contains sixteen non-inverting buffers with 3-STATE outputs. The device is nibble (4 bits) controlled with each nibble functioning identically, but independent of the other. The control pins can be shorted together to obtain full 16-bit operation.

## **Logic Diagram**



## **Schematic of each Output**



## **Absolute Maximum Ratings**(Note 1)

Storage Temperature -65°C to +150°C Ambient Temperature under Bias -55°C to +125°C

Junction Temperature under Bias  $-55^{\circ}C$  to  $+150^{\circ}C$ -0.5V to +7.0V

V<sub>CC</sub> Pin Potential to Ground Pin

Input Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Any Output

in the Disabled or

Power-Off State -0.5V to 5.5Vin the HIGH State  $-0.5\mbox{V}$  to  $\mbox{V}_{\mbox{CC}}$ 

Current Applied to Output

twice the rated  $I_{OL}$  (mA) in LOW State (Max) DC Latchup Source Current -500 mA

Over Voltage Latchup (I/O) 10V

## **Recommended Operating Conditions**

-40°C to +85°C Free Air Ambient Temperature Supply Voltage +4.5V to +5.5V

Minimum Input Edge Rate ( $\Delta V/\Delta t$ )

50 mV/ns Data Input 20 mV/ns Enable Input

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation

under these conditions is not implied. Note 2: Either voltage limit or current limit is sufficient to protect inputs.

## **DC Electrical Characteristics**

Symbol	Paramet	er	Min	Тур	Max	Units	V <sub>CC</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage		2.0			V		Recognized HIGH Signal
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltag	е			-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage		2.5			V	Min	$I_{OH} = -3 \text{ mA}$
			2.0			V	Min	$I_{OH} = -32 \text{ mA}$
V <sub>OL</sub>	Output LOW Voltage				8.0	V	Min	I <sub>OL</sub> = 12 mA
I <sub>IH</sub>	Input HIGH Current				1	μА	Max	V <sub>IN</sub> = 2.7V (Note 3)
					1	μΛ	IVIAX	$V_{IN} = V_{CC}$
I <sub>BVI</sub>	Input HIGH Current Break	down Test			7	μΑ	Max	$V_{IN} = 7.0V$
I <sub>IL</sub>	Input LOW Current				-1	μА	Max	V <sub>IN</sub> = 0.5V (Note 3)
					-1	μΛ	IVIAX	$V_{IN} = 0.0V$
V <sub>ID</sub>	Input Leakage Test		4.75			V	0.0	$I_{ID} = 1.9 \mu\text{A}$
								All Other Pins Grounded
I <sub>OZH</sub>	Output Leakage Current				10	μΑ	0 – 5.5V	$V_{OUT} = 2.7V; \overline{OE}_n = 2.0V$
I <sub>OZL</sub>	Output Leakage Current				-10	μΑ	0 – 5.5V	$V_{OUT} = 0.5V; \overline{OE}_n = 2.0V$
Ios	Output Short-Circuit Curre	ent	-100		-275	mA	Max	V <sub>OUT</sub> = 0.0V
I <sub>CEX</sub>	Output High Leakage Cur	rent			50	μΑ	Max	$V_{OUT} = V_{CC}$
I <sub>ZZ</sub>	Bus Drainage Test				100	μΑ	0.0	V <sub>OUT</sub> = 5.5V; All Others GND
I <sub>CCH</sub>	Power Supply Current				2.0	mA	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current				60	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current				2.0	mA	Max	$\overline{OE}_n = V_{CC}$
								All Others at V <sub>CC</sub> or GND
I <sub>CCT</sub>	Additional I <sub>CC</sub> /Input	Outputs Enabled			3.0	mA		$V_I = V_{CC} - 2.1V$
		Outputs 3-STATE			3.0	mA	Max	Enable Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V
		Outputs 3-STATE			50	μΑ		Data Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V
								All Others at V <sub>CC</sub> or GND
I <sub>CCD</sub>	Dynamic I <sub>CC</sub>	No Load				mA/	May	Outputs OPEN
	(Note 3)				0.1	MHz	Max	$\overline{OE}_n = GND$
								One Bit Toggling, 50% Duty Cycle

Note 3: Guaranteed, but not tested.

## **AC Electrical Characteristics**

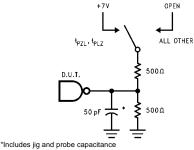
Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5V$ $C_L = 50 \text{ pF}$		$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V} - 5.5\text{V}$ $C_L = 50 \text{ pF}$		Units	
		Min	Тур	Max	Min	Max	
t <sub>PLH</sub>	Propagation	1.0	2.4	3.9	1.0	3.9	ns
t <sub>PHL</sub>	Delay Data to Outputs	1.0	3.2	4.7	1.0	4.7	115
t <sub>PZH</sub>	Output	1.5	3.5	6.3	1.5	6.3	200
$t_{PZL}$	Enable Time	1.5	4.2	6.9	1.5	6.9	ns
t <sub>PHZ</sub>	Output	1.0	4.2	6.7	1.0	6.7	20
t <sub>PLZ</sub>	Disable Time	1.0	3.8	6.7	1.0	6.7	ns

## Capacitance

Symbol	Parameter	Тур	Units	Conditions T <sub>A</sub> = 25°C
C <sub>IN</sub>	Input Capacitance	5.0	pF	V <sub>CC</sub> = 0.0V
C <sub>OUT</sub> (Note 4)	Output Capacitance	9.0	pF	V <sub>CC</sub> = 5.0V

Note 4:  $C_{OUT}$  is measured at frequency f = 1 MHz per MIL-STD-883, Method 3012.

## **AC Loading**



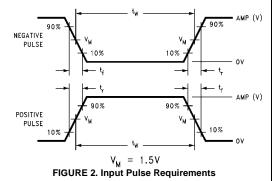


FIGURE 1. Standard AC Test Load

Amplitude	Rep. Rate	t <sub>W</sub>	t <sub>r</sub>	t <sub>f</sub>
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns

FIGURE 3. Test Input Signal Requirements

#### **AC Waveforms**

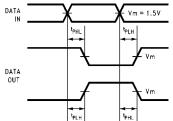


FIGURE 4. Propagation Delay Waveforms for Inverting and Non-Inverting Functions

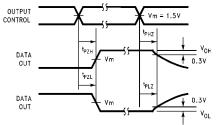


FIGURE 6. 3-STATE Output HIGH and LOW Enable and Disable Times

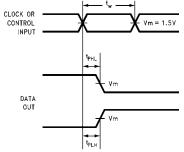


FIGURE 5. Propagation Delay, Pulse Width Waveforms

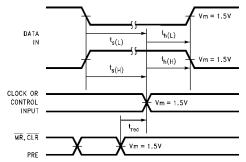
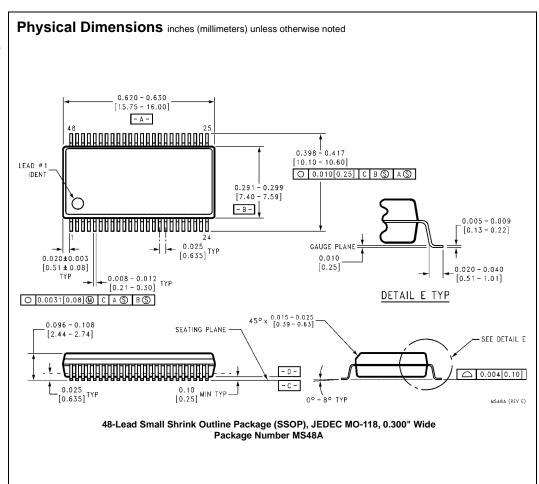
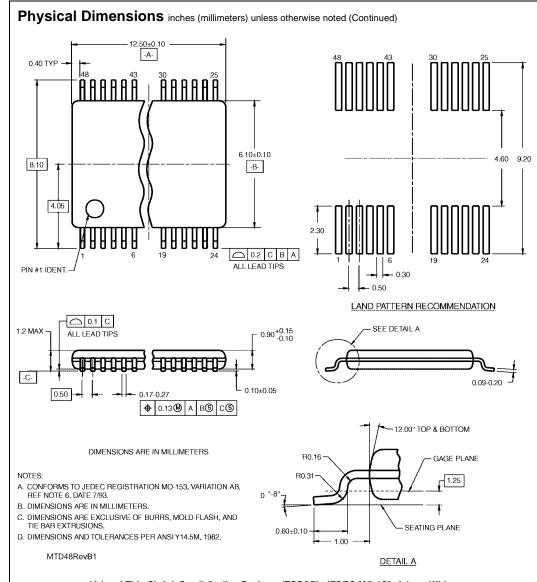


FIGURE 7. Setup Time, Hold Time and Recovery Time Waveforms





## 48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide Package Number MTD48

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